TECHNICAL SPECIFICATION

SPÉCIFICATION TECHNIQUE

TECHNISCHE SPEZIFIKATION

CEN ISO/TS 80004-6

May 2015

ICS 07.030; 01.040.07

English Version

Nanotechnologies - Vocabulary - Part 6: Nano-object characterization (ISO/TS 80004-6:2013)

Nanotechnologies - Vocabulaire - Partie 6: Caractérisation des nano-objets (ISO/TS 80004-6:2013)

Nanotechnologien - Fachwörterverzeichnis - Teil 6: Charakterisierung von Nanoobjekten (ISO/TS 80004-6:2013)

This Technical Specification (CEN/TS) was approved by CEN on 16 May 2015 for provisional application.

The period of validity of this CEN/TS is limited initially to three years. After two years the members of CEN will be requested to submit their comments, particularly on the question whether the CEN/TS can be converted into a European Standard.

CEN members are required to announce the existence of this CEN/TS in the same way as for an EN and to make the CEN/TS available promptly at national level in an appropriate form. It is permissible to keep conflicting national standards in force (in parallel to the CEN/TS) until the final decision about the possible conversion of the CEN/TS into an EN is reached.

CEN members are the national standards bodies of Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and United Kingdom.

EUROPEAN COMMITTEE FOR STANDARDIZATION
COMITÉ EUROPÉEN DE NORMALISATION
EUROPÄISCHES KOMITEE FÜR NORMUNG

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Ref. No. CEN ISO/TS 80004-6:2015 E

Foreword

The text of ISO/TS 80004-6:2013 has been prepared by Technical Committee ISO/TC 229 “Nanotechnologies” of the International Organization for Standardization (ISO) and has been taken over as CEN ISO/TS 80004-6:2015 by Technical Committee CEN/TC 352 “Nanotechnologies” the secretariat of which is held by AFNOR.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN [and/or CENELEC] shall not be held responsible for identifying any or all such patent rights.

According to the CEN-CENELEC Internal Regulations, the national standards organizations of the following countries are bound to announce this Technical Specification: Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.

Endorsement notice

The text of ISO/TS 80004-6:2013 has been approved by CEN as CEN ISO/TS 80004-6:2015 without any modification.

Contents

Page

Introduction

Measurement and instrumentation techniques have effectively opened the door to modern nanotechnology. Characterization is key to understanding the properties and function of all nano-objects.

Nano-object characterization involves interactions between people with different backgrounds and from different fields. Those interested in nano-object characterization might, for example, be materials scientists, biologists, chemists or physicists and might have a background that is primarily experimental or theoretical. Those making use of the data extend beyond this group to include regulators and toxicologists. To avoid any misunderstandings, and to facilitate both comparability and the reliable exchange of information, it is essential to clarify the concepts, to establish the terms for use and to establish their definitions.

The terms are classified under the following broad headings:

— Clause 2: General terms

— Clause 3: Terms related to size and shape measurement

— Clause 4: Terms related to chemical analysis

— Clause 5: Terms related to measurement of other properties

These headings are intended as guide only, as some techniques can determine more than one property. Subclause 3.1 lists the overarching measurands that apply to the rest of Clause 3. Other measurands are more technique specific and are placed in the text adjacent to the technique.

It should be noted that most techniques require analysis in a non-native state and involve sample preparation, for example placing the nano-objects on a surface or placing it in a specific fluid or vacuum. This could change the nature of the nano-objects.

The order of the techniques in this document should not be taken to indicate a preference and the techniques listed in this document are not intended to be exhaustive. Equally, some of the techniques listed in this document are more popular than others in their usage in analysing certain properties of nano-objects. Table 1 lists alphabetically the main current techniques for nano-object characterization.

Table 1 — Alphabetical list of main current techniques for nano-object characterization

Property	Current main techniques
Size	atomic force microscopy (AFM), centrifugal liquid sedimentation (CLS), differential mobility analysing system (DMAS), dynamic light scattering (DLS), scanning electron microscopy (SEM), particle tracking analysis (PTA), transmission electron microscopy (TEM)
Shape	atomic force microscopy (AFM), scanning electron microscopy (SEM), transmission electron microscopy (TEM)
Surface area	Brunauer-Emmett-Teller (BET) method
‘Surface’ chemistry	secondary ion mass spectrometry (SIMS), X-ray photoelectron spectroscopy (XPS)
Chemistry of the ‘bulk’ sample	inductively coupled plasma mass spectrometry (ICP-MS), nuclear magnetic resonance spectroscopy (NMR)
Charge in suspensions	zeta potential

This document is intended to serve as a starting reference for the vocabulary that underpins measurement and characterization efforts in the field of nanotechnologies.

Nanotechnologies — Vocabulary —

Part 6:
Nano-object characterization

1 Scope

This Technical Specification lists terms and definitions relevant to the characterization of nano-objects.

2 General terms

2.1
nanoscale
size range from approximately 1 nm to 100 nm

Note 1 to entry: Properties that are not extrapolations from a larger size will typically, but not exclusively, be exhibited in this size range. For such properties the size limits are considered approximate.

Note 2 to entry: The lower limit in this definition (approximately 1 nm) is introduced to avoid single and small groups of atoms from being designated as *nano-objects* (2.2) or elements of nanostructures, which might be implied by the absence of a lower limit.

[SOURCE: ISO/TS 80004-1:2010, definition 2.1]

2.2
nano-object
material with one, two or three external dimensions in the *nanoscale* (2.1)

Note 1 to entry: Generic term for all discrete nanoscale objects.

[SOURCE: ISO/TS 80004-1:2010, definition 2.5]

2.3
nanoparticle
nano-object (2.2) with all three external dimensions in the *nanoscale* (2.1)

Note 1 to entry: If the lengths of the longest to the shortest axes of the nano-object differ significantly (typically by more than three times), the terms *nanofibre* (2.6) or *nanoplate* (2.4) are intended to be used instead of the term nanoparticle.

[SOURCE: ISO/TS 27687:2008, definition 4.1]

2.4
nanoplate
nano-object (2.2) with one external dimension in the *nanoscale* (2.1) and the two other external dimensions significantly larger

Note 1 to entry: The smallest external dimension is the thickness of the nanoplate.

Note 2 to entry: The two significantly larger dimensions are considered to differ from the nanoscale dimension by more than three times.

Note 3 to entry: The larger external dimensions are not necessarily in the nanoscale.

[SOURCE: ISO/TS 27687:2008, definition 4.2]